

Notice of References Cited	Application/Control No. 10/594,052		Applicant(s)/Patent Under Reexamination SCHULZ ET AL.	
	Examiner JOHN WASAFF		Art Unit 3742	Page 1 of 1

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	U	Siegman, Lasers, 1986, University Science Books, Ch. 17, pp. 663-666.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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